<span id="page-0-0"></span>

#### **FEATURES**

- **High dynamic range, dual DAC parts**
- **Low noise and intermodulation distortion**
- **Single carrier W-CDMA ACLR = 80 dBc @ 61.44 MHz IF**
- **Innovative switching output stage permits usable outputs beyond Nyquist frequency**
- **LVDS inputs with dual-port or optional interleaved singleport operation**
- **Differential analog current outputs are programmable from 8.6 mA to 31.7 mA full scale**
- **Auxiliary 10-bit current DACs with source/sink capability for external offset nulling**
- **Internal 1.2 V precision reference voltage source**
- **Operates from 1.8 V and 3.3 V supplies**
- **315 mW power dissipation**
- **Small footprint, RoHS compliant, 72-lead LFCSP**

#### **APPLICATIONS**

**Wireless infrastructure W-CDMA, CDMA2000, TD-SCDMA, WiMAX Wideband communications LMDS/MMDS, point-to-point RF signal generators, arbitrary waveform generators** 

# Dual 12-/14-/16-Bit, LVDS Interface 600 MSPS DACs AD9780/AD9781/AD9783

#### **GENERAL DESCRIPTION**

The AD9780/AD9781/AD9783 include pin-compatible, high dynamic range, dual digital-to-analog converters (DACs) with 12-/14-/16-bit resolutions, and sample rates of up to 600 MSPS. The devices include specific features for direct conversion transmit applications, including gain and offset compensation, and they interface seamlessly with analog quadrature modulators such as the [ADL5370](http://www.analog.com/ADL5370).

A proprietary, dynamic output architecture permits synthesis of analog outputs even above Nyquist by shifting energy away from the fundamental and into the image frequency.

Full programmability is provided through a serial peripheral interface (SPI) port. Some pin-programmable features are also offered for those applications without a controller.

#### **PRODUCT HIGHLIGHTS**

- 1. Low noise and intermodulation distortion (IMD) enable high quality synthesis of wideband signals.
- 2. Proprietary switching output for enhanced dynamic performance.
- 3. Programmable current outputs and dual auxiliary DACs provide flexibility and system enhancements.



**Rev. 0** 

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#### **REVISION HISTORY**

11/07-Revision 0: Initial Version

### <span id="page-2-1"></span><span id="page-2-0"></span>**SPECIFICATIONS**

#### **DC SPECIFICATIONS**

 $T<sub>MIN</sub>$  to  $T<sub>MAX</sub>$ , AVDD33 = 3.3 V, DVDD33 = 3.3 V, DVDD18 = 1.8 V, CVDD18 = 1.8 V, I<sub>OUTFS</sub> = 20 mA maximum sample rate, unless otherwise noted.

#### **Table 1.**



<sup>1</sup> Based on a 10 kΩ external resistor.<br><sup>2</sup> forc = 500 MSPS, four = 20 MHz

 $^{2}$  f<sub>DAC</sub> = 500 MSPS, f<sub>OUT</sub> = 20 MHz.

#### <span id="page-3-1"></span><span id="page-3-0"></span>**DIGITAL SPECIFICATIONS**

 $T<sub>MIN</sub>$  to  $T<sub>MAX</sub>$ , AVDD33 = 3.3 V, DVDD33 = 3.3 V, DVDD18 = 1.8 V, CVDD18 = 1.8 V, I<sub>OUTFS</sub> = 20 mA maximum sample rate, unless otherwise noted.

### **Table 2.**



#### **AC SPECIFICATIONS**

 $T<sub>MIN</sub>$  to  $T<sub>MAX</sub>$ , AVDD33 = 3.3 V, DVDD33 = 3.3 V, DVDD18 = 1.8 V, CVDD18 = 1.8 V, I<sub>OUTFS</sub> = 20 mA, maximum sample rate, unless otherwise noted.

#### **Table 3.**



### <span id="page-4-1"></span><span id="page-4-0"></span>ABSOLUTE MAXIMUM RATINGS

#### **Table 4.**



#### **THERMAL RESISTANCE**

Thermal resistance is tested using A JEDEC standard 4-layer thermal test board with no airflow.

#### **Table 5.**



Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

#### **ESD CAUTION**



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

### <span id="page-5-0"></span>PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



**Table 6. AD9780 Pin Function Descriptions** 





**Table 7. AD9781 Pin Function Descriptions** 





**Table 8. AD9783 Pin Function Descriptions** 



### <span id="page-8-0"></span>TYPICAL PERFORMANCE CHARACTERISTICS



Figure 7. AD9783 INL, TA = −40°C, FS = 20 mA









Figure 17. AD9783 SFDR vs. fout over f<sub>DAC</sub> in Baseband and Mix Modes,  $FS = 20$  mA



Figure 18. AD9783 SFDR vs. fout over Analog Output,  $T_A = 25^{\circ}$ C, at 600 MSPS



 $T_A = 25^{\circ}$ C, at 600 MSPS, FS = 20 mA



Figure 20. AD9783 SFDR vs.  $f_{OUT}$  over Temperature, at 600 MSPS, FS = 20 mA



Figure 21. AD9783 IMD vs. fout over f<sub>DAC</sub> in Baseband and Mix Modes,  $FS = 20$  mA



Figure 22. AD9783 IMD vs.  $f_{OUT}$  over Analog Output,  $T_A = 25^{\circ}$ C, at 600 MSPS



Figure 23. AD9783 IMD vs. fout over Digital Input Level,  $T_A = 25^{\circ}C$ , at 600 MSPS, FS = 20 mA



Figure 24. AD9783 IMD vs.  $f_{OUT}$  over Temperature, at 600 MSPS, FS = 20 mA



Figure 25. AD9783 One-Tone NSD vs.  $f_{\text{OUT}}$  over  $f_{\text{DAC}}$  Baseband and Mix Modes,  $FS = 20$  mA



Figure 26. AD9783 Eight-Tone NSD vs. fout over f<sub>DAC</sub> Baseband and Mix Modes, FS = 20 mA



Figure 27. AD9783 One-Tone NSD vs. four over Temperature, at 600 MSPS,  $FS = 20$  mA



Figure 28. AD9783 Eight-Tone NSD vs. four over Temperature, at 600 MSPS, FS  $= 20$  mA



Figure 29. AD9783 ACLR for First Adjacent Band 1-Carrier W-CDMA Baseband and Mix Modes,  $FS = 20$  mA



Figure 30. AD9783 ACLR for Second Adjacent Band 1-Carrier W-CDMA Baseband and Mix Modes, FS = 20 mA



Figure 31. AD9783 ACLR for Third Adjacent Band 1-Carrier W-CDMA Baseband and Mix Modes, FS = 20 mA



Figure 32. AD9783 ACLR for First Adjacent Channel 2-Carrier W-CDMA over Digital Input Level Baseband and Mix Modes, at 491.52 MSPS, FS = 20 mA



Figure 33. AD9783 ACLR for Second Adjacent Channel 2-Carrier W-CDMA over Digital Input Level Baseband and Mix Modes, at 491.52 MSPS, FS = 20 mA



Figure 34. AD9783 ACLR for Third Adjacent Channel 2-Carrier W-CDMA over Digital Input Level Baseband and Mix Modes, at 491.52 MSPS, FS = 20 mA



Figure 35. AD9783 ACLR for First Adjacent Channel 4-Carrier W-CDMA over Digital Input Level Baseband and Mix Modes, at 491.52 MSPS, FS = 20 mA



Figure 36. AD9783 ACLR for Second Adjacent Channel 4-Carrier W-CDMA over Digital Input Level Baseband and Mix Modes, at 491.52 MSPS,  $FS = 20$  mA



Figure 37. AD9783 ACLR for Third Adjacent Channel 4-Carrier W-CDMA over Digital Input Level Baseband and Mix Modes, at 491.52 MSPS, FS = 20 mA



Figure 38. Nominal Power in the Fundamental, FS = 20 mA, at 600 MSPS,  $FS = 20$  mA





Figure 40. AD9781 DNL, FS = 20 mA



Figure 41. AD9781 SFDR vs. fout in Baseband and Mix Modes, at 600 MSPS,  $FS = 20$  mA



Figure 42. AD9781 IMD vs. fout in Baseband and Mix Modes, at 600 MSPS,  $FS = 20$  mA



Figure 43. AD9781 One-Tone, Eight-Tone NSD vs. fout in Baseband and Mix Modes, at  $600$  MSPS, FS = 20 mA



Figure 44. AD9781 ACLR for 1-Carrier W-CDMA Baseband and Mix Modes, at 491.52 MSPS, FS = 20 mA









Figure 47. AD9780 SFDR vs. fout in Baseband and Mix Modes, at 600 MSPS,  $FS = 20$  mA



Figure 48. AD9780 IMD vs.  $f_{\text{OUT}}$  in Baseband and Mix Modes, at 600 MSPS,  $FS = 20$  mA



Figure 49. AD9780 One-Tone, Eight-Tone NSD vs.  $f_{OUT}$  in Baseband and Mix Modes, at 600 MSPS, FS = 20 mA



Figure 50. AD9780 ACLR for 1-Carrier W-CDMA Baseband and Mix Modes, at 491.52 MSPS, FS = 20 mA

### <span id="page-16-0"></span>**TERMINOLOGY**

#### **Linearity Error or Integral Nonlinearity (INL)**

Linearity error is defined as the maximum deviation of the actual analog output from the ideal output, determined by a straight line drawn from zero scale to full scale.

#### **Differential Nonlinearity (DNL)**

DNL is the measure of the variation in analog value, normalized to full scale, associated with a 1 LSB change in digital input code.

#### **Monotonicity**

A DAC is monotonic if the output either increases or remains constant as the digital input increases.

#### **Offset Error**

Offset error is the deviation of the output current from the ideal of zero. For I<sub>OUTA</sub>, 0 mA output is expected when the inputs are all 0s. For I<sub>OUTB</sub>, 0 mA output is expected when all inputs are set to 1s.

#### **Gain Error**

Gain error is the difference between the actual and ideal output span. The actual span is determined by the difference between the output when all inputs are set to 1s and the output when all inputs are set to 0s.

#### **Output Compliance Range**

Output compliance range is the range of allowable voltage at the output of a current-output DAC. Operation beyond the maximum compliance limits can cause either output stage saturation or breakdown, resulting in nonlinear performance.

#### **Temperature Drift**

Temperature drift is specified as the maximum change from the ambient (25 $^{\circ}$ C) value to the value at either  $T_{\text{MIN}}$  or  $T_{\text{MAX}}$ . For offset and gain drift, the drift is reported in ppm of fullscale range (FSR) per degree Celsius. For reference drift, the drift is reported in ppm per degree Celsius.

#### **Power Supply Rejection**

Power supply rejection is the maximum change in the full-scale output as the supplies are varied from minimum to maximum specified voltages.

#### **Settling Time**

Settling time is the time required for the output to reach and remain within a specified error band around its final value, measured from the start of the output transition.

#### **Spurious Free Dynamic Range (SFDR)**

SFDR is the difference, in decibels, between the peak amplitude of the output signal and the peak spurious signal between dc and the frequency equal to half the input data rate.

#### **Total Harmonic Distortion (THD)**

THD is the ratio of the rms sum of the first six harmonic components to the rms value of the measured fundamental. It is expressed as a percentage or in decibels.

#### **Signal-to-Noise Ratio (SNR)**

SNR is the ratio of the rms value of the measured output signal to the rms sum of all other spectral components below the Nyquist frequency, excluding the first six harmonics and dc. The value for SNR is expressed in decibels.

#### **Adjacent Channel Leakage Ratio (ACLR)**

ACLR is the ratio in dBc between the measured power within a channel relative to its adjacent channel.

#### **Complex Image Rejection**

In a traditional two-part upconversion, two images are created around the second IF frequency. These images usually waste transmitter power and system bandwidth. By placing the real part of a second complex modulator in series with the first complex modulator, either the upper or lower frequency image near the second IF can be rejected.

### <span id="page-17-1"></span><span id="page-17-0"></span>THEORY OF OPERATION

The AD9780/AD9781/AD9783 combine many features to make them very attractive for wired and wireless communications systems. The dual DAC architecture facilitates easy interface to common quadrature modulators when designing single sideband transmitters. In addition, the speed and performance of the devices allow wider bandwidths and more carriers to be synthesized than in previously available products.

All features and options are software programmable through the SPI port.

#### **SERIAL PERIPHERAL INTERFACE**



06936-051

The serial peripheral interface (SPI) port is a flexible, synchronous serial communications port allowing easy interface to many industry-standard microcontrollers and microprocessors. The port is compatible with most synchronous transfer formats including both the Motorola SPI® and Intel® SSR protocols.

The interface allows read and write access to all registers that configure the AD9780/AD9781/AD9783. Single or multiple byte transfers are supported as well as MSB-first or LSB-first transfer formats. Serial data input/output can be accomplished through a single bidirectional pin (SDIO) or through two unidirectional pins (SDIO/SDO).

The serial port configuration is controlled by Register 0x00, Bits<7:6>. It is important to note that any change made to the serial port configuration occurs immediately upon writing to the last bit of this byte. Therefore, it is possible with a multibyte transfer to write to this register and change the configuration in the middle of a communication cycle. Care must be taken to compensate for the new configuration within the remaining bytes of the current communication cycle.

Use of a single-byte transfer when changing the serial port configuration is recommended to prevent unexpected device behavior.

#### **GENERAL OPERATION OF THE SERIAL INTERFACE**

There are two phases to any communication cycle with the AD9780/AD9781/AD9783: Phase 1 and Phase 2. Phase 1 is the instruction cycle, which writes an instruction byte into the device. This byte provides the serial port controller with information regarding Phase 2 of the communication cycle: the data transfer cycle.

The Phase 1 instruction byte defines whether the upcoming data transfer is a read or write, the number of bytes in the data transfer, and a reference register address for the first byte of the data transfer. A logic high on the CSB pin followed by a logic low resets the SPI port to its initial state and defines the start of the instruction cycle. From this point, the next eight rising SCLK edges define the eight bits of the instruction byte for the current communication cycle.

The remaining SCLK edges are for Phase 2 of the communication cycle, which is the data transfer between the serial port controller and the system controller. Phase 2 can be a transfer of 1, 2, 3, or 4 data bytes as determined by the instruction byte. Using multibyte transfers is usually preferred, although single-byte data transfers are useful to reduce CPU overhead or when only a single register access is required.

All serial port data is transferred to and from the device in synchronization with the SCLK pin. Input data is always latched on the rising edge of SCLK whereas output data is always valid after the falling edge of SCLK. Register contents change immediately upon writing to the last bit of each transfer byte.

Any time synchronization is lost, the device has the ability to asynchronously terminate an I/O operation whenever the CSB pin is taken to logic high. Any unwritten register content data is lost if the I/O operation is aborted. Taking CSB low then resets the serial port controller and restarts the communication cycle.

#### **INSTRUCTION BYTE**

The instruction byte contains the information shown in Table 9.

#### **Table 9.**



Bit 7, R/W, determines whether a read or a write data transfer occurs after the instruction byte write. Logic 1 indicates a read operation. Logic 0 indicates a write operation.

Bits<6:5>, N1 and N0, determine the number of bytes to be transferred during the data transfer cycle. The bits decode as shown in Table 10.

#### **Table 10. Byte Transfer Count**



<span id="page-18-0"></span>Bits<4:0>, A4, A3, A2, A1, and A0, determine which register is accessed during the data transfer of the communication cycle. For multibyte transfers, this address is a starting or ending address depending on the current data transfer mode. For MSB-first format, the specified address is an ending address or the most significant address in the current cycle. Remaining register addresses for multiple byte data transfers are generated internally by the serial port controller by decrementing from the specified address. For LSB-first format, the specified address is a beginning address or the least significant address in the current cycle. Remaining register addresses for multiple byte data transfers are generated internally by the serial port controller by incrementing from the specified address.

#### **MSB/LSB TRANSFERS**

The serial port can support both MSB-first and LSB-first data formats. This functionality is controlled by Register 0x00, Bit 6. The default is Logic 0, which is MSB-first format.

When using MSB-first format (LSBFIRST =  $0$ ), the instruction and data bit must be written from MSB to LSB. Multibyte data transfers in MSB-first format start with an instruction byte that includes the register address of the most significant data byte. Subsequent data bytes are loaded into sequentially lower address locations. In MSB-first mode, the serial port internal address generator decrements for each byte of the multibyte data transfer.

When using LSB-first format (LSBFIRST  $= 1$ ), the instruction and data bit must be written from LSB to MSB. Multibyte data transfers in LSB-first format start with an instruction byte that includes the register address of the least significant data byte. Subsequent data bytes are loaded into sequentially higher address locations. In LSB-first mode, the serial port internal address generator increments for each byte of the multibyte data transfer.

Use of a single-byte transfer when changing the serial port data format is recommended to prevent unexpected device behavior.

#### **SERIAL INTERFACE PORT PIN DESCRIPTIONS**

#### **Chip Select Bar (CSB)**

Active low input starts and gates a communication cycle. It allows more than one device to be used on the same serial communication lines. CSB must stay low during the entire communication cycle. Incomplete data transfers are aborted any time the CSB pin goes high. SDO and SDIO pins go to a high impedance state when this input is high.

#### **Serial Clock (SCLK)**

The serial clock pin is used to synchronize data to and from the device and to run the internal state machines. The maximum frequency of SCLK is 40 MHz. All data input is registered on the rising edge of SCLK. All data is driven out on the falling edge of SCLK.

#### **Serial Port Data I/O (SDIO)**

Data is always written into the device on this pin. However, SDIO can also function as a bidirectional data output line. The configuration of this pin is controlled by Register 0x00, Bit 7. The default is Logic 0, which configures the SDIO pin as unidirectional.

#### **Serial Port Data Output (SDO)**

Data is read from this pin for protocols that use separate lines for transmitting and receiving data. The configuration of this pin is controlled by Register 0x00, Bit 7. If this bit is set to a Logic 1, the SDO pin does not output data and is set to a high impedance state.









### <span id="page-19-0"></span>SPI REGISTER MAP

**Table 11.** 



### <span id="page-20-0"></span>SPI REGISTER DESCRIPTIONS

Reading these registers returns previously written values for all defined register bits, unless otherwise noted.





#### <span id="page-22-0"></span>**SPI PORT, RESET, AND PIN MODE**

In general, when the AD9780/AD9781/AD9783 are powered up, an active high pulse applied to the RESET pin should follow. This ensures the default state of all control register bits. In addition, once the RESET pin goes low, the SPI port can be activated, thus CSB should be held high.

For applications without a controller, the AD9780/AD9781/ AD9783 also supports pin mode operation, which allows some functional options to be pin selected without the use of the SPI port. Pin mode is enabled any time the RESET pin is held high. In pin mode, the four SPI port pins take on secondary functions as shown in Table 13.

**Table 13. SPI Pin Functions (Pin Mode)** 

Pin	
<b>Name</b>	<b>Pin Mode Function</b>
<b>SDIO</b>	DATA (Register 0x02, Bit 7), bit value (1/0) equals pin state (high/low).
<b>CSB</b>	Enable mix mode. If CSB is high, Register 0x0A is set to 0x05, putting both DAC1 and DAC2 into mix mode.
<b>SDO</b>	Enable full power-down. If SDO is high, Register 0x03 is set to 0xFF.

### <span id="page-23-1"></span><span id="page-23-0"></span>PARALLEL DATA PORT INTERFACE

The parallel port data interface consists of 18 differential LVDS signals, DCO, DCI, and the sixteen DATA lines (DATA<15:0>), as shown in [Figure 56](#page-23-2). DCO is the output clock generated by the AD9780/AD9781/AD9783 that is used to clock out the data from the digital data engine. The DATA lines transmit the multiplexed I and Q data words for the I and Q DACs, respectively. DCI provides timing information about the parallel data and signals the I/Q status of the data.

As shown in [Figure 56,](#page-23-2) the incoming LVDS data is latched by an internally generated clock referred to as the data sampling signal (DSS). DSS is a delayed version of the main DAC clock signal, CLKP/CLKN. Optimal positioning of the rising and falling edges of DSS with respect to the incoming DATA signals results in the most robust transmission of the DAC data. Positioning the edges of DSS with respect to the DATA signals is achieved by selecting the value of a programmable delay element, SMP. A procedure for determining the optimal value of SMP is given in the [Optimizing the Parallel Port](#page-23-3)  [Timing](#page-23-3) section.

<span id="page-23-4"></span>In addition to properly positioning the DSS edges, maximizing the opening of the eye in the DCLK\_IN and DATA signals improves the reliability of the data port interface. The two sources of degradation that reduce the eye in the DCLK\_IN and DATA signals are the jitter on these signals and the skew between them. Therefore, it is recommended that the DCLK\_IN be generated in the same manner as the DATA signals with the same output driver and data line routing. In other words, it should be implemented as a seventeenth DATA line with an alternating (010101…) bit sequence.



Figure 56. Digital Data Port Block Diagram

#### <span id="page-23-3"></span><span id="page-23-2"></span>**OPTIMIZING THE PARALLEL PORT TIMING**

Before outlining the procedure for determining the delay for SMP (that is, the positioning of DSS with respect to the DATA signals), it is worthwhile to describe the simplified block diagram of the digital data port. As can be seen in [Figure 56,](#page-23-2) the DATA signals are sampled on the rising and falling edges of DSS. From there, the data is demultiplexed and retimed before being sent to the DACs.

The DCLK\_IN signal provides timing information about the parallel data as well as indicating the destination (that is, I DAC or Q DAC) of the data. A delayed version of DCI is generated by a delay element, SET, and is referred to as DDCI. DDCI is sampled by a delayed version of the DSS signal, labeled as DDSS in [Figure 56](#page-23-2). DDSS is simply DSS delayed by a period of time, HLD. The pair of delays, SET and HLD, allows accurate timing information to be extracted from DCLK\_IN. Increasing the delay of the HLD block results in DCLK\_IN being sampled later in its cycle. Increasing the delay of the SET block results in DCLK\_IN being sampled earlier in its cycle. The result of this sampling is stored and can be queried by reading the SEEK bit. Since DSS and DCLK\_IN are the same frequency, the SEEK bit should be a constant value. By varying the SET and HLD delay blocks and seeing the effect on the SEEK bit, the setupand-hold timing of DSS with respect to DCLK\_IN (and hence, DATA) can be measured.



The incremental units of SET, HLD, and SMP are in units of real time, not fractions of a clock cycle. The nominal step size for SET and HLD is 80 ps. The nominal step size for SMP is 160 ps. Note that the value of SMP refers to Register 5, Bits<4:0>, SET refers to Register 4, Bits<7:4>, and HLD refers to Register 4, Bits<3:0>.

A procedure for configuring the device to ensure valid sampling of the DATA signals follows. Generally speaking, the procedure begins by building an array of setup-and-hold values as the sample delay is swept through a range of values. Based on this information, a value of SMP is programmed to establish an optimal sampling point. This new sampling point is then double-checked to verify that it is optimally set.

#### <span id="page-24-0"></span>**Building the Array**

The following procedure can be used to build the array.

- 1. Set the values of SMP, SET, and HLD to zero. Read and record the value of the SEEK bit.
- 2. With SMP and SET set to 0, increment the HLD value until the SEEK bit toggles and record the HLD value. This measures the hold time as shown in [Figure 57](#page-23-4).
- 3. With SMP and HLD set to 0, increment the SET value until the SEEK bit toggles and record the SET value. This measures the setup time as shown in [Figure 57.](#page-23-4)
- 4. Set the value of SET and HLD to 0. Increment the value of SMP and record the value of the SEEK bit.
- 5. Increment HLD until the SEEK bit toggles and record the HLD value. Set HLD to 0 and increment SET until the SEEK bit toggles and record the SET value.
- 6. Repeat Step 4 and Step 5 until the procedure has been completed for SMP values from 0 to 31.

Note that while building the table, a value for either SET or HLD may not be found to make the SEEK bit toggle. In this case, assume a value of 15.

[Table 14](#page-24-0) shows example arrays taken at DAC sample rates of 200 MHz, 400 MHz, and 600 MHz. It should be noted that the delay from the DCO input to the DCI output of the data source has a profound effect on when the SEEK bit toggles over the range of SMP values. Therefore, the tables generated in any particular system do not necessarily match the example timing data arrays in [Table 14](#page-24-0).

	$f_{DACCLK} = 200 MHz$			$f_{DACCLK} = 400 MHz$			$f_{DACCLK} = 600 MHz$		
<b>SMP</b>	<b>SEEK</b>	<b>SET</b>	<b>HLD</b>	<b>SEEK</b>	<b>SET</b>	<b>HLD</b>	<b>SEEK</b>	<b>SET</b>	<b>HLD</b>
0	0	6	15	0	$\overline{2}$	13	$\pmb{0}$	0	11
1	$\mathbf 0$	8	15	0	$\overline{4}$	11	0	$\overline{2}$	9
$\overline{\mathbf{c}}$	0	10	15	0	6	9	0	3	7
3	0	12	15	0	8	7	0	5	5
4	0	15	15	0	10	4	0	8	$\overline{\mathbf{c}}$
5	0	15	13	0	12	2	0	10	1
6	0	15	11	0	14	1	$\mathbf{1}$	1	9
7	0	15	9	1	$\mathbf{1}$	13	$\mathbf{1}$	$\overline{2}$	$\overline{7}$
8	0	15	7	1	3	11	1	4	4
9	0	15	5	1	4	9	1	7	$\overline{2}$
$10$	0	15	3	1	6	7	1	9	1
11	0	15	1	1	8	5	0	1	10
12	0	15	0	1	10	3	0	2	8
13	1	1	15	1	12	$\mathbf{1}$	0	4	7
14	1	$\overline{4}$	15	0	0	15	0	6	$\overline{4}$
15	1	6	15	0	$\overline{\mathbf{2}}$	13	0	9	$\overline{2}$
16	1	8	15	0	$\overline{4}$	11	0	11	0
17	1	10	15	0	6	9	$\mathbf{1}$	1	8
18	1	12	15	0	7	7	$\mathbf{1}$	3	7
19	1	13	15	0	9	5	1	5	5
20	1	15	13	0	11	3	$\mathbf{1}$	7	2
21	1	15	11	0	13	1	$\mathbf{1}$	9	$\mathbf{1}$
22	1	15	9	0	15	0	0	1	10
23	1	15	7	1	2	11	0	$\mathbf 2$	8
24	1	15	5	1	$\overline{4}$	9	0	$\overline{4}$	6
25	1	15	3	1	6	7	0	$\overline{7}$	4
26	1	15	1	1	8	5	0	9	$\overline{2}$
27	1	15	0	1	9	3	0	10	0
28	0	1	15	1	11	$\overline{\mathbf{c}}$	$\mathbf{1}$	1	8
29	0	1	15	1	11	2	1	1	8
30	0	1	15	1	11	2	1	1	8
31	0	1	15	1	11	2	1	1	8

**Table 14. Timing Data Arrays** 

#### <span id="page-25-0"></span>**Determining the SMP Value**

Once the timing data array has been built, the value of SMP can be determined using the following procedure.

- 1. Look for the SMP value that corresponds to the 0 to 1 transition of the SEEK bit in the table. In the 600 MHz case from [Table 14](#page-24-0), this occurs for an SMP value of 6.
- 2. Look for the SMP value that corresponds to the 1 to 0 transition of the SEEK bit in the table. In the 600 MHz case from [Table 14](#page-24-0), this occurs for an SMP value of 11.
- 3. The same two values found in Step 1 and Step 2 indicate the valid sampling window. In the 600 MHz case, this occurs for an SMP value of 11.
- 4. The optimal SMP value in the valid sampling window is where the following two conditions are true: SET < HLD and |HLD-SET| is smallest value.

In the 600 MHz case, the optimal SMP value is 7.

After programming the calculated value of SMP (referred to as SMP<sub>OPTIMAL</sub>), the configuration should be tested to verify that there is sufficient timing margin. This can be accomplished by ensuring that the SEEK bit reads back as a 1 for SMP values equal to  $SMP<sub>OPTIMAL</sub> + 1$  and  $SMP<sub>OPTIMAL</sub> - 1$ . Also, it should be noted that the sum of SET and HLD should be a minimum of 8. If the sum is lower than this, then you should check for excessive jitter on the DCLK\_IN line, and that the frequency of DCLK\_IN does not exceed the data sheet maximum of 600 MHz (or 1200 Mbps).

<span id="page-25-2"></span>As mentioned previously, low jitter and skew between the input data bits and DCI are critical for reliable operation at the maximum input data rates. [Figure 58](#page-25-1) shows the eye diagram for the input data signals that were used to collect the data in [Table 14](#page-24-0).



<span id="page-25-3"></span><span id="page-25-1"></span>Figure 58. Eye Diagram of Data Source Used in Building the 600 MHz Timing Data Array of [Table 14](#page-24-0) 

Over temperature, the valid sampling window shifts. Therefore, when operating the device over 500 MHz, the timing should be optimized again whenever the device undergoes a temperature change of more than 20°C. Another consideration in the timing of the digital data port is the propagation delay variation from

DCLK\_OUT to DCLK\_IN. If this varies significantly over time (more than 25% of SET or HLD) due to temperature changes or other effects, repeat this timing calibration procedure.

At sample rates of ≤400 MSPS, the interface timing is sufficient to allow for a simplified procedure. In this case, the SEEK bit can be recorded as SMP is swept through the range from 0 to 31. The center of the first valid sampling window can then be chosen as the optimal value of SMP. Using the 400 MHz case from [Table 14](#page-24-0) as an example, the first valid sampling window occurs for SMP values of 7 to 13. The center of this window is 10, so 10 can be used as the optimal SMP value.

#### **DRIVING THE CLK INPUT**

The CLK input requires a low jitter differential drive signal. It is a PMOS input differential pair powered from the 1.8 V supply: therefore, it is important to maintain the specified 400 mV input common-mode voltage. Each input pin can safely swing from 200 mV p-p to 1 V p-p about the 400 mV common-mode voltage. While these input levels are not directly LVDS-compatible, CLK can be driven by an offset ac-coupled LVDS signal, as shown in [Figure 59](#page-25-2).



If a clean sine clock is available, it can be transformer-coupled to CLKP and CLKN as shown in [Figure 60.](#page-25-3) Use of a CMOS or TTL clock is also acceptable for lower sample rates. It can be routed through a CMOS-to-LVDS translator, then ac-coupled, as described in this section. Alternatively, it can be transformercoupled and clamped, as shown in [Figure 60](#page-25-3).



Figure 60. TTL or CMOS DAC CLK Drive Circuit

A simple bias network for generating the 400 mV commonmode voltage is shown in [Figure 61.](#page-26-1) It is important to use CVDD18 and CGND for the clock bias circuit. Any noise or other signal coupled onto the clock is multiplied by the DAC digital input signal and can degrade the DAC's performance.

<span id="page-26-0"></span>

#### <span id="page-26-1"></span>**FULL-SCALE CURRENT GENERATION**

#### **Internal Reference**

Full-scale current on the I DAC and Q DAC can be set from 8.66 mA to 31.66 mA. Initially, the 1.2 V band gap reference is used to set up a current in an external resistor connected to FS ADJ (Pin 54). A simplified block diagram of the reference circuitry is shown in [Figure 62](#page-26-2). The recommended value for the external resistor is 10 kΩ, which sets up an IREFERENCE in the resistor of 120 μA, which in turn provides a DAC output fullscale current of 20 mA. Because the gain error is a linear function of this resistor, a high precision resistor improves gain matching to the internal matching specification of the devices. Internal current mirrors provide a current-gain scaling, where I DAC or Q DAC gain is a 10-bit word in the SPI port register. The default value for the DAC gain registers gives a full-scale current output  $(I<sub>FS</sub>)$  of approximately 20 mA, where  $I<sub>FS</sub>$  is equal to

$$
I_{FS} = (86.6 + (0.220 \times DAC gain)) \times 1000/R
$$

<span id="page-26-2"></span>

#### **DAC TRANSFER FUNCTION**

Each DAC output of the AD9780/AD9781/AD9783 drives two complementary current outputs, I<sub>OUTP</sub> and I<sub>OUTN</sub>. I<sub>OUTP</sub> provides a near I<sub>FS</sub> when all bits are high. For example,

 $DAC$  *CODE* =  $2^N - 1$ 

where *N* = 12-/14-/16-bits for AD9780/AD9781/AD9783 (respectively), while IOUTN provides no current.

The current output appearing at  $I<sub>OUTP</sub>$  and  $I<sub>OUTN</sub>$  is a function of both the input code and I<sub>FS</sub> and can be expressed as

$$
I_{\text{OUTP}} = (DAC\,DATA/2^N) \times I_{FS} \tag{1}
$$

$$
I_{\text{OUTN}} = ((2^N - 1) - DAC \, DATA)/2^N \times I_{FS} \tag{2}
$$

where *DAC DATA* = 0 to  $2^N - 1$  (decimal representation).

The two current outputs typically drive a resistive load directly or via a transformer. If dc coupling is required, IouTP and IouTN should be connected to matching resistive loads  $(R_{LOAD})$  that are tied to analog common (AVSS). The single-ended voltage output appearing at the IOUTP and IOUTN pins is

$$
V_{\text{OUTP}} = I_{\text{OUTP}} \times R_{\text{LOAD}} \tag{3}
$$

$$
V_{OUTN} = I_{OUTN} \times R_{LOAD}
$$
 (4)

Note that to achieve the maximum output compliance of 1 V at the nominal 20 mA output current, R<sub>LOAD</sub> must be set to 50  $\Omega$ . Also note that the full-scale value of  $\rm V_{\rm OUTP}$  and  $\rm V_{\rm OUTN}$  should not exceed the specified output compliance range to maintain specified distortion and linearity performance.

There are two distinct advantages to operating the AD9780/ AD9781/AD9783 differentially. First, differential operation helps cancel common-mode error sources associated with  $I<sub>OUTP</sub>$ and I<sub>OUTN</sub>, such as noise, distortion, and dc offsets. Second, the differential code dependent current and subsequent output voltage ( $V<sub>DIFF</sub>$ ) is twice the value of the single-ended voltage output (V<sub>OUTP</sub> or V<sub>OUTN</sub>), providing  $2 \times$  signal power to the load.

$$
V_{\text{DIFF}} = (I_{\text{OUTP}} - I_{\text{OUTN}}) \times R_{\text{LOAD}} \tag{5}
$$

#### **ANALOG MODES OF OPERATION**

The AD9780/AD9781/AD9783 utilize a proprietary quadswitch architecture that lowers the distortion of the DAC by eliminating a code dependent glitch that occurs with conventional dual-switch architectures. This architecture eliminates the code dependent glitches, but creates a constant glitch at a rate of  $2 \times$ f<sub>DAC</sub>. For communications systems and other applications requiring good frequency domain performance from the DAC, this is seldom problematic.

The quad-switch architecture also supports two additional modes of operation: mix mode and return-to-zero mode. The waveforms of these two modes are shown in [Figure 64.](#page-27-0) In mix mode, the output is inverted every other half clock cycle. This effectively chops the DAC output at the sample rate. This chopping has the effect of frequency shifting the sinc roll-off from dc to fDAC. Additionally, there is a second subtle effect on the

output spectrum. The shifted spectrum is also shaped by a **Auxiliary DACs**  second sinc function with a first null at  $2 \times f_{\text{DAC}}$ . The reason for this shaping is that the data is not continuously varying at twice the clock rate, but is simply repeated.

In return-to-zero mode, the output is set to midscale every other half clock cycle. The output is similar to the DAC output in normal mode except that the output pulses are half the width and half the area. Because the output pulses have half the width, the sinc function is scaled in frequency by two and has a first null at  $2 \times f_{\text{DAC}}$ . Because the area of the pulses is half that of the pulses in normal mode, the output power is half the normal mode output power.



Figure 64. Mix Mode and Return-to-Zero Mode DAC Waveforms

<span id="page-27-2"></span><span id="page-27-0"></span>France Contract and CLO performs of the contract of the contract of the pass pass<br>  $\begin{array}{ccc}\n1/1 & \text{if } 1/1 & \text{if }$ The functions that shape the output spectrums for the three modes of operation, normal mode, mix mode, and return-tozero mode, are shown in [Figure 65.](#page-27-1) Switching between the analog modes reshapes the sinc roll-off inherent at the DAC output. This ability to change modes in the AD9780/AD9781/ AD9783 make the parts suitable for direct IF applications. The user can place a carrier anywhere in the first three Nyquist zones depending on the operating mode selected. The performance and maximum amplitude in all three Nyquist zones is impacted by this sinc roll-off depending on where the carrier is placed, as shown in [Figure 65](#page-27-1).



<span id="page-27-3"></span><span id="page-27-1"></span>Figure 65. Transfer Function for Each Analog Operating Mode

Two auxiliary DACs are provided on the AD9780/AD9781/ AD9783. A functional diagram is shown in [Figure 66.](#page-27-2) The auxiliary DACs are current output devices with two output pins, AUXP and AUXN. The active pin can be programmed to either source or sink current. When either sinking or sourcing, the full-scale current magnitude is 2 mA. The available compliance range at the auxiliary DAC outputs depends on whether the output is configured to sink or source current. When sourcing current, the compliance voltage is 0 V to 1.6 V, but when sinking current the output compliance voltage is reduced to 0.8 V to 1.6 V. Either output can be used, but only one output of the AUX DAC (P or N) is active at any time. The inactive pin is always in a high impedance state (>100 kΩ).



Figure 66. Auxiliary DAC Functional Diagram

In a single sideband transmitter application, the combination of the input referred dc offset voltage of the quadrature modulator and the DAC output offset voltage can result in local oscillator (LO) feedthrough at the modulator output, which degrades system performance. The auxiliary DACs can be used to remove the dc offset and the resulting LO feedthrough. The circuit configuration for using the auxiliary DACs for performing dc offset correction depends on the details of the DAC and modulator interface. An example of a dc-coupled configuration with lowpass filtering is shown in [Figure 67](#page-27-3).



Figure 67. DAC DC-Coupled to Quadrature Modulator with a Passive DC Shift

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#### <span id="page-28-0"></span>**POWER DISSIPATION**

[Figure 68](#page-28-1) through [Figure 73](#page-28-2) show the power dissipation of the part in single DAC and dual DAC modes.

<span id="page-28-1"></span>

<span id="page-28-2"></span>Figure 70. Power Dissipation, Digital 3.3 V Supply, Analog 3.3 V Supply, I Data Only



Figure 72. Power Dissipation, Digital 1.8 V Supply, Clock 1.8 V Supply, I and Q Data, Dual DAC Mode



Figure 73. Power Dissipation, Digital 3.3 V Supply, Analog 3.3 V Supply, I and Q Data, Dual DAC Mode

### <span id="page-29-1"></span><span id="page-29-0"></span>OUTLINE DIMENSIONS



Figure 74. 72-Lead Lead Frame Chip Scale Package [LFCSP\_VQ] 10 mm × 10 mm, Very Thin Quad  $(CP-72-1)$ Dimensions shown in millimeters

#### **ORDERING GUIDE**



1 Z = RoHS Compliant Part.

### **NOTES**

### **NOTES**

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![](_page_31_Picture_3.jpeg)

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